# APPROVAL SHEET



CUSTOMER:	
DESCRIPTION:	HC-49/SMD 20.000MHz Quartz Crystal Resonator
MANUFACTURER PART NO.:	FTX20.000M20SM-30/30B
CUSTOMER PART NO:	
USED IN MODEL:	
REVISION	A1

	承	认	APP	PROVAL
工程部	E E	质部		采购部
TECHNOLOGY DEPT.	QUAL	LITY DEPT.	PU	URCHASING DEPT.

Date: September 19, 2017

Rev	Revise page	Revise contents	<u>Date</u>	Ref.No.	<u>Reviser</u>
A1	ALL	Initial released		N/A	DavidJiang

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### 1. QUARTZ CRYSTAL UNIT SPECIFICATION

1.1 Frequency: 20.000MHz

1.2 Mode of Oscillation AT Fundamental

1.3 Holder type : HC-49/SMD

1.4 Frequency tolerance: ±30ppm at 25℃

1.5 Equivalent series resistance (Rr):  $40\Omega$  Max.

1.6 Operating temperature range: -20°C To +70°C

1.7 Storage temperature range:  $-40^{\circ}$ C To +85°C

1.8 Frequency stability: ±30ppm at -20℃ To +70℃

1.9 Loading capacitance (CL): 20.0pF

1.10 Drive level (DL): 100 uW Typical

1.11 Shunt Capacitance (C0): 7.0pF MAX

1.12 Insulation resistance (IR): More than 500M ohms at DC 100V

1.13 Circuit: Measured in S&A 250B

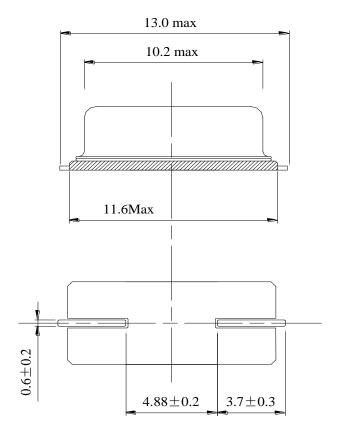
1.14 Aging:  $\pm 5$  ppm Max (+25°C 1<sup>st</sup> Year)

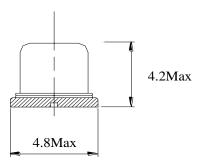
1.15 Dimensions and marking Refer to page.3

1.16 Emboss carrier tape & reel Refer to page.4

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## 2. MARKING & DIMENSIONS





\*Marking should be printed as following:

Logo, Nominal Frequency

Logo:

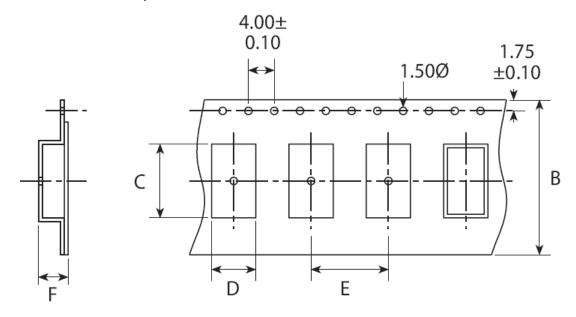
Nominal Frequency: (ex. 8.000 MHz→8.000)

Marking: Laser marking

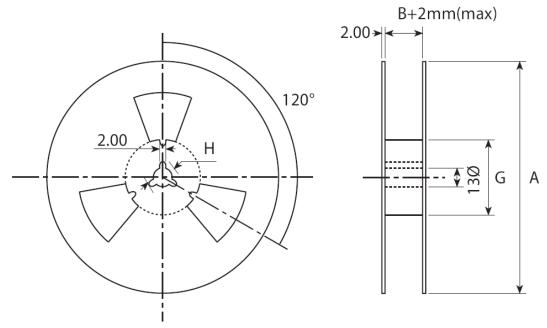
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## **3.CARRIER TAPE & REEL**

### a.) Dimensions of Carrier Tape



#### b.) Dimensions of Reel



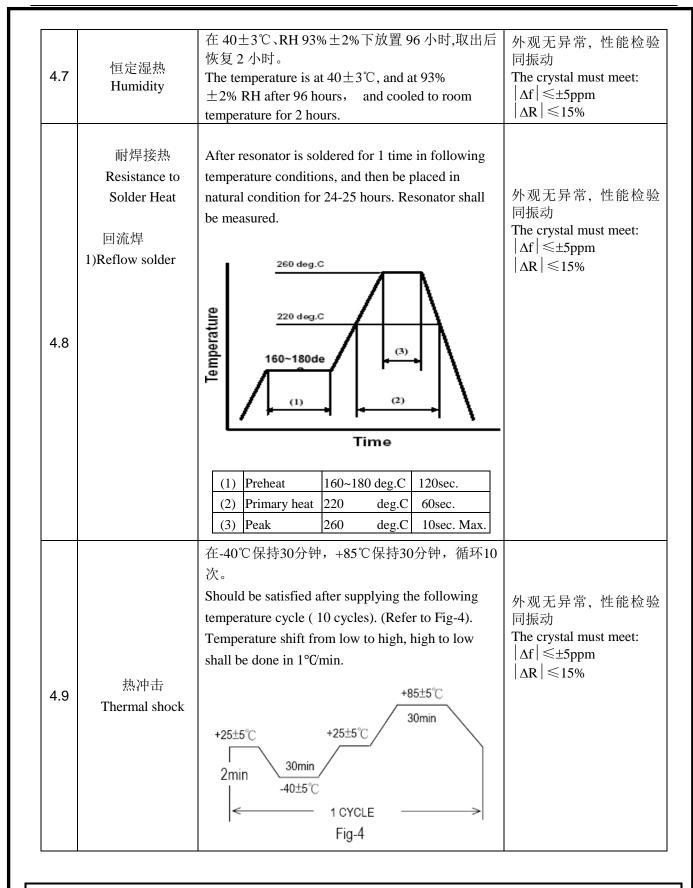
	A	В	С	D	E	F	G
49SMD	330±2.0	24±0.2	13.9	5.6	12.0	4.8	100

1000 pieces of crystal unit per reel

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	4.MECHANICAL/ENVIRONMENTAL CHARACTERISTICS					
NO.	项 目 ITEM	条 件 CONDITIONS	规 格 SPECIFICATIONS			
4.1	漏气试验 Leaking Test	完全浸入 90±3℃热水中 3 分钟。 Fully immersed into hot water at 90℃±3℃ for 3 minutes.  用氦质谱仪测试或酒精加压法测试绝缘电阻。 Take measurements with a helium leakage detector,or measure insulation resistance under pressure.	无气泡存在 no air bubble are visible.  1×10 <sup>-8</sup> Pa.m <sup>3</sup> /s Max or IR≥500M Ω			
4.2	跌落试验 Drop Test	高度 75cm,自由落体于 3cm 木板上,6次 Dropping 6 times from the height of 75 cm onto hard wooden board of thickness more than 30mm.	频率变化±5ppm 以内, 电阻变化±15%以内 The crystal must meet:  Δf ≤±5ppm  ΔR ≤15%			
4.3	振动试验 Vibration Test	频率 10~55Hz,振幅 1.5mm,时间 1.5 分钟循环,在 XYZ 方向各 2 小时。 Vibration Frequency: 10~55Hz Cycle: 1.5 Min. Amplitude: 1.5mm P-P. Direction: X.Y.Z Time: 2 Hours / Each Direction	频率变化±5ppm 以内, 电阻变化±15%以内 The crystal must meet:  Δf ≤±5ppm  ΔR ≤15%			
4.4	可 焊 性 Solderability Test	从引线末端至距底部 $2mm$ 处放入 $230$ $\mathbb{C} \pm 5$ $\mathbb{C}$ 焊槽内,时间: $5\pm 0.5$ 秒。 The terminal lead wire is to be soaked in a $230$ $\mathbb{C}$ $\pm 5$ $\mathbb{C}$ tin trough for $5\pm 0.5$ seconds.	沾锡面≥90%.频率变化±5ppm 以 内,电阻变化±15%以内 Tin over the wire≥90% The crystal must meet:   Δf   ≤±5ppm   ΔR   ≤15%			
4.5	耐低温性 Low Temperature Enduring	在-40℃±3℃下放置 96 小时,取出后在常温下恢复 2 小时。 The samples crystal is to be tested after being placed in the environment of -40±3℃ for 96 hours, and recovered to room temperature for 2 hours.	频率变化±5ppm 以内, 电阻变化±15%以内 The crystal must meet:  Δf ≤±5ppm  ΔR ≤15%			
4.6	耐高温性 High Temperature Enduring	在+85℃±3℃下放置 96 小时,取出后在常温下恢复 2 小时。 The samples crystal is to be tested after being heated at +85±3℃ for 96 hours, and cooled to room temperature for 2 hours.	频率变化±5ppm 以内, 电阻变化±15%以内 The crystal must meet:  Δf ≤±5ppm  ΔR ≤15%			

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